

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 53080
	:	
Yoshiyuki TANI, et al.	:	Confirmation Number: 5502
	:	
Application No.: 10/593,822	:	Group Art Unit: 1645
	:	
Filed: September 22, 2006	:	Examiner: Not Yet Assigned
	:	
For: GLASS IDENTIFICATION METHOD AND GLASS IDENTIFICATION APPARATUS (as amended)		

INFORMATION DISCLOSURE STATEMENT

Mail Stop IDS
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(PTO-1449)

 ATTY. DOCKET NO.
076476-0012

 SERIAL NO.
10/593,822

 APPLICANT
Yoshiyuki TANI, et al.

 FILING DATE
**September 22,
2006**

 GROUP
1645

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code(s) (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
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FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
		JP 11-51884	02/26/1999	Mitsubishi Heavy Ind. Ltd	With English abstract		
		JP 11-174005	07/02/1999	Horiba Ltd	With English abstract		
		JP 02-273439	11/07/1990	Fujitsu Ltd	With English abstract		

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.
		Yasuhiro SUZUKI et al., "FORENSIC DISCRIMINATION OF HEADLIGHT GLASS BY ANALYSIS OF TRACE IMPURITIES WITH SYNCHROTRON RADIATION X-RAY FLUORESCENCE SPECTROMETRY AND ICP-MS" (English abstract)
		"Kahangata Keiko X-sen Bunseki Sochi ni yoru Shutsudo ibutsu no Sonoba Bunseki" (English Translation attached)

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.